

# 8×8 photodiode array based on P-*InAsSbP*/n-*InAs* single heterostructure

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There have been considerable progress over the last decade in developing *InAs* homojunction photodiodes (PDs) including the p-i-n PD arrays for fast response sensing of IR radiation around 3  $\mu\text{m}$  [1]. *InAs* based heterojunction photodiodes, e.g. *InAsSbP/InAs* based ones, potentially offer high  $R_0A$  product values but most of related investigations were devoted to PDs with abrupt impurity distribution near a p-n junction that is not optimal for high speed operation. To the best of our knowledge there has been only one paper describing operation of *InAs* heterostructure array near room temperature [2], however room temperature detectivity value was not high enough for some of the sensing applications.

The report presents characterization of P-*InAsSbP*/n-*InAs*/n<sup>+</sup>-*InAs*(100) single heterostructure PD array of 8×8 dimensions in the 77-385 K temperature range.

Wafers onto heavily doped n<sup>+</sup>-*InAs* (*Sn*) (100) substrates with an electron concentration of  $n^+ = (2-3) \cdot 10^{18} \text{ cm}^{-3}$  contained two epitaxial layers: 3-4  $\mu\text{m}$  thick n-*InAs* active region and P-*InAsSbP* (*Zn*) ( $E_g \approx 0.48 \text{ eV}$ , 77 K,  $P = (2-5) \cdot 10^{17} \text{ cm}^{-3}$ ) cap layer. Monolithic 8×8 matrix contained 64 individually addressable PD elements of  $\sim 190 \times 190 \mu\text{m}$  size.

Capacitance measurements revealed no impact of the frequency on zero bias capacitance in the 0-2 MHz range and showed reverse cubic dependence on bias suggesting nearly linear impurity distribution near a p-n junction. I- $V_{\text{FB}}$  curve ideality factor exhibited minima around 200 K ( $\beta = 1.03$ ) and reached  $\beta = 1.2$  value at low and elevated temperatures showing negligible influence of tunneling. The latter together with the independence of the ( $C^{-3}$ )- $V$  slope on temperature states negligible influence or lack of deep recombination centers in P-*InAsSbP*/n-*InAs* single heterostructures under study. As a result nearly unity internal quantum efficiency and nice PD operating parameters have been achieved at low temperatures including low capacitance ( $10^{-7} \text{ F} \cdot \text{cm}^{-2}$ , 77 K) and high detectivity values in the thermoelectric range of temperatures and BLIP operation at  $\sim 200 \text{ K}$ .

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## References

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2. N.D.Il'inskaya, S.A.Karandashev, N.G.Karpukhina, A.A.Lavrov, B.A.Matveev, M.A.Remennyi, N.M.Stus', and A.A.Usikova, Applied Physics, issue 6, Pages 47-51(2014).

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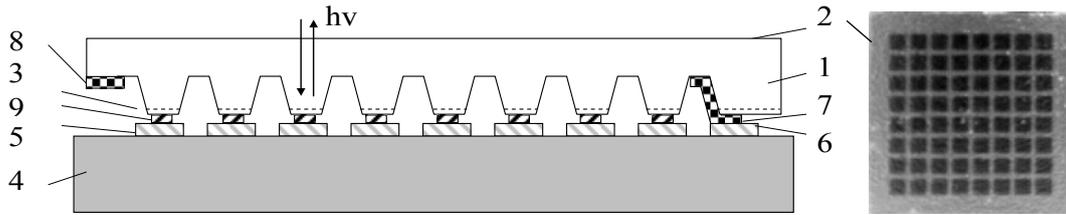


Fig.1. Schematic (left) and IR image ( $I_{RB}=-2$  mA, right) of the BSI array. 1-  $P\text{-InAsSbP}/n\text{-InAs}/n^+\text{-InAs}$  single heterostructure, 2  $n^+\text{-InAs}$  surface, 3 – mesa walls/p-n junction, 4 –  $\text{Si}$  read-out plate, 5 – anode bonding pads, 6 – cathode bonding pad, 7 – contact to  $n^+\text{-InAs}$ , 8 –ring contact to  $n^+\text{-InAs}$ , 9 – contacts to individual anodes. Items 7 and 8 have short circuit.

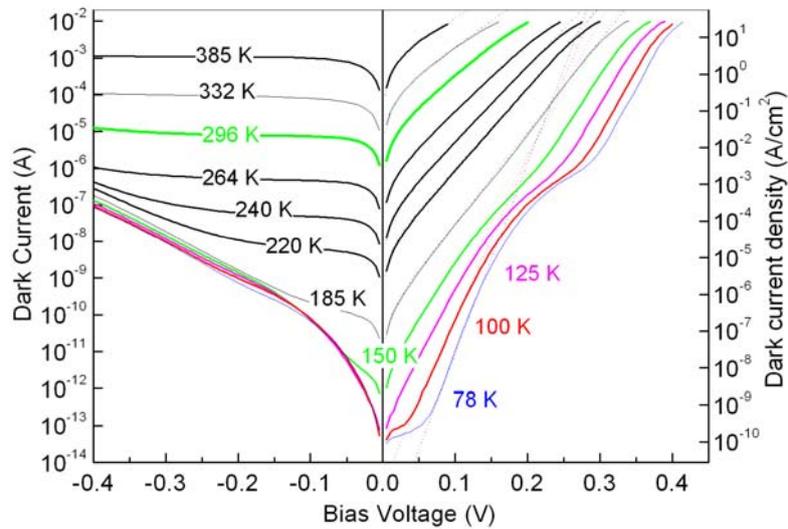


Fig.2. I-V characteristics of the single array element in the 73-385 K temperature range..

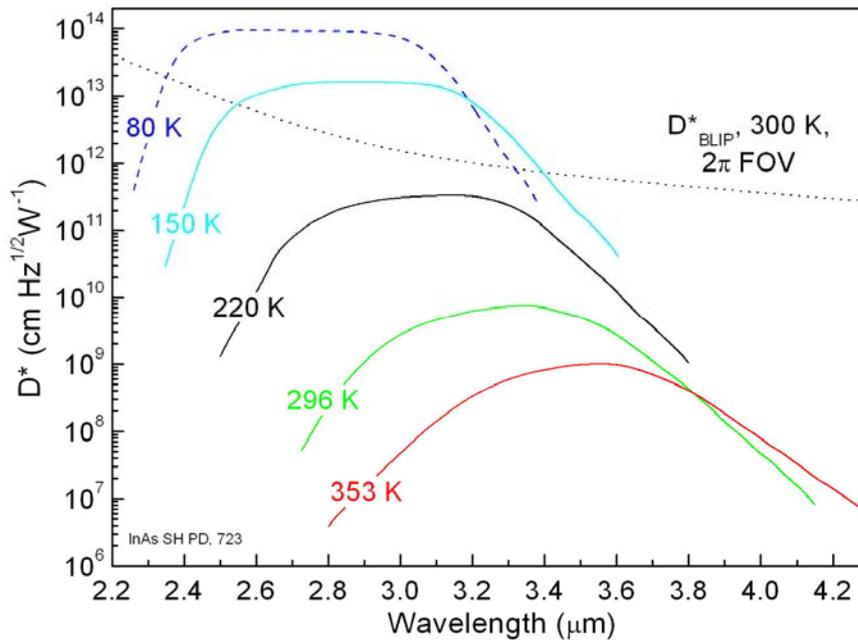


Fig.3. Detectivity spectra of a single array element at 80, 150, 220, 296 and 353 K.